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| Notice of References Cited | Application/Control No. 10/529,669 | Applicant(s)/Patent Under Reexamination HEKSTRA ET AL. | |
| | Examiner Jean W. Désir | Art Unit 2622 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-6,147,720 A | 11-2000 | Guerinot et al. | 348/744 |
| * | B | US-6,252,636 B1 | 06-2001 | Bartlett, Terry A. | 348/743 |
| * | C | US-6,469,821 B2 | 10-2002 | Bartlett et al. | 359/292 |
| * | D | US-6,505,939 B1 | 01-2003 | Bierhuizen et al. | 353/94 |
| * | E | US-6,545,814 B2 | 04-2003 | Bartlett et al. | 359/636 |
| * | F | US-6,758,579 B2 | 07-2004 | Ishikawa et al. | 362/238 |
| * | G | US-6,972,736 B1 | 12-2005 | Wada et al. | 345/32 |
| * | H | US-7,053,880 B2 | 05-2006 | Lim et al. | 345/102 |
| * | I | US-7,180,554 B2 | 02-2007 | Divelbiss et al. | 348/742 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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| | P | | | | | |
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| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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